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03226.06500

Application Number

Applicant(s)

Claude R. Gauthier et al.

Filing Date

March 28, 2001

Group Art Unit

11099 v. S. PTO.



U.S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

[illegible]

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

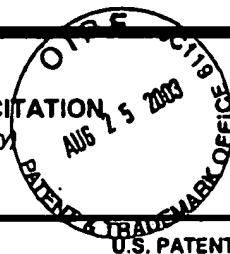
	A1	IEEE Transactions on Advanced Packaging, August 1999, Vol. 22, No. 3, pages 284-291: "Power Distribution System Design Methodology and Capacitor Selection for Modern CMOS Technology", L. D. Smith, R. E. Anderson, D. W. Forehand, T. J. Pelc and T. Roy.
	A2	IEEE Transactions on Advanced Packaging, August 1999, Vol. 22, No. 3, pages 240-248: "Modeling of Power Distribution Systems for High Performance Microprocessors", Dennis J. Herrell and Benjamin Beker.

EXAMINER

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

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AUG 28 2003

Technology Center 2100

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>KSM</i>	B1	"Parasitic Resistance in an MOS Transistor Used as On-Chip Decoupling Capacitance" as published in IEEE JOURNAL OF SOLID-STATE CIRCUITS, Vol. 32, No. 4, April 1997 Author: Patrik Larsson (pages 574-576)
<i>KSM</i>	B2	"Power Supply Noise in Future IC's: A Crystal Ball Reading" as published in IEEE 1999 CUSTOM INTEGRATED CIRCUITS CONFERENCE Author: P. Larsson (pages 467-474)

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